

# Effect of Single Atom Doping on Structural, Electronic and Magnetic Properties of Hexagonal Silicon Carbide (4H-SiC) for Spintronic Application: A first principle study

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## Abstract

In this paper, the structural geometry, electronic and magnetic properties of single magnesium (Mg) and vanadium (V) atoms doped 4H-SiC system were investigated. For the structural geometry of each sample, the energy substitution, as well as bond length, were calculated; results obtained indicate that the bond length of Silicon-Magnesium (Si-Mg) and Silicon-Vanadium (Si-V) was 1.90 Å and 2.02 Å respectively, greater than that of silicon-carbon (Si-C) 1.89 Å in pure SiC. This result indicates that the bond length increases due to the introduction of dopants with greater radii than that of Si. It also shows that both Mg and V doping changes the structure from non-magnetic ordering to magnetic in nature. The band structure result for both undoped and doped shows the presence of valence band maximum (VBM) and conduction band minimum (CBM) around different symmetry points which indicate an indirect band gap nature. The calculated band gap of pure 4H SiC is found to be ~ 2.21 eV, which is at a wide band gap material range, but with the introduction of Mg and V dopants, the band gap reduced significantly to ~0.4 eV and ~0.45 eV respectively. The density of state (DOS) and projected density of state (PDOS) show the contributions of the various states in both the VBM and CBM; after doping the Fermi energy is shifted towards higher energy and enters into the conduction band, exhibiting spin polarization. Both DOS and PDOS indicated that the magnetic moments mainly come from the 2p orbitals of Si atoms and 3p for Mg dopant and 3d orbitals for V dopant. The magnetic moment for 4H-SiC/Mg and 4H-SiC/V was calculated to be 2.23  $\mu\text{B}$  and 3.24  $\mu\text{B}$ .

Keywords: Hexagonal Silicon carbide (4H-SiC); Substitutional Doping; Electronic; Magnetic properties; Quantum ESPRESSO.

## I. INTRODUCTION

Si  
Silicon carbide (SiC) has been used as an industrial material since the last century, with methods of its

synthesis introduced as far back as 1885 [1]. Silicon carbide has been recognized as an important structural ceramic material because of its unique combination of properties, such as excellent oxidation resistance, high wear resistance,

high thermal conductivity and good thermal shock resistance. Such a combination of properties is determined by the highly covalent (up to 88%) chemical bonding between silicon and carbon atoms. However, this very same bonding presents a problem in dense SiC production using powder technology due to the extremely low self-diffusion coefficient, densification of the SiC powders alone is possible only at extremely high pressure and/or temperatures exceeding 2100 °C. To densify SiC successfully the use of sintering aids is necessary [2].

Silicon carbide (SiC), also known as carborundum is a semiconductor containing silicon and carbon. It occurs in nature as the extremely rare mineral moissanite. Synthetic SiC powder has been mass-produced since 1893 for use as an abrasive. Grains of silicon carbide can be bonded together by sintering to form very hard ceramics that are widely used in applications requiring high endurance, such as car brakes, car clutches and ceramic plates in bulletproof vests [3].

SiC normally come in different polycrystalline types, of which 3C, 4H, and 6H are the most common ones. Moreover, 4H-SiC is suitable for manufacturing high-power electronic devices because of its large forbidden bandwidth (3.26 eV), good thermal conductivity, and relatively small anisotropy [4-6].

To date, research on the growth of 4H-SiC has achieved great success [7-9]. Doping along Carbon has shown strong and harmful effects on the carrier lifetime of 4H-SiC [10, 11]. Previous studies used electron paramagnetic resonance to show doping along carbon in P-type 4H-SiC annealed at high temperatures and analyzed the influence of external environmental changes on the defects, but some basic electrical properties of  $V_C^+$  defects remain to be characterized [12]. Doping in SiC was theoretically studied by employing pseudo-potential calculations without full ionic relaxations and using only a small supercell [13]. Recent studies have performed accurate pseudo-potential calculations with full ionic relaxations employing a large supercell [14-15]. Nevertheless, the present understanding of doping in SiC remains incomplete.

## II. COMPUTATIONAL METHOD

The first-principles calculations were carried out using the Quantum ESPRESSO code [15], which is based on the plane-wave pseudo-potential (PWP) method [16]. We have adopted an exchange-correlation function treated by Generalized Gradient Approximation (GGA) [17] and Perdew–Burke–Ernzerhof (PBE) [18]. We used 4H-SiC hexagonal structure with the experimental lattice  $a = 3.041 \text{ \AA}$ ,  $c = 9.952 \text{ \AA}$  and space group  $P6_3/mmc$  obtained from the online experimental database [19] as shown in Fig. 1(a). For doping, a model of  $2 \times 2 \times 2$  4H-SiC supercell with 64 atoms was generated using XCrystden software [20] shown in Fig. 1(b). In each case, a single Mg and V atoms were replaced with one Si which is equivalent to 1.56% doping concentration. Both pure and doped systems were optimized

using Broyden-Fletcher-Goldfarb-Shanno (BFGS) approximation with  $12 \times 12 \times 1$  and  $8 \times 8 \times 1$  Monkhorst-Pack k-points [21] within the Brillion zone respectively. In each, both atomic positions and lattice parameters were optimized until the atomic forces and stresses were smaller than  $0.01 \text{ eV/\AA}$  and  $0.02 \text{ GPa}$  respectively. A plane wave energy cutoff of 330 eV and 300 eV are used for the pure and doped systems respectively. The valence electron configurations of Mg-doped 3C-SiC are  $3d^8 4s^2$  for V-doped,  $3s^2 3p^2$ .

## III. RESULTS AND DISCUSSION

### A. Structural Geometry

Fig. 1 (a) shows our optimized structure. The structure is three-dimensional. There are two equivalent Si sites. In the first Si site, Si(1) is bonded to one C(1) and three equivalent C(2) atoms to form a corner-sharing SiC4 tetrahedral. The Si(1)–C(1) bond length is 1.90 Å. All Si(1)–C(2) bond lengths are 1.90 Å. In the second Si site, Si(2) is bonded to one C(2) and three equivalent C(1) atoms to form a corner-sharing SiC4 tetrahedral. The Si(2)–C(2) bond length is 1.90 Å. All Si(2)–C(1) bond lengths are 1.89 Å. There are two equivalent C sites. In the first C site, C(1) is bonded to one Si(1) and three equivalent Si(2) atoms to form a corner-sharing CSi4 tetrahedral. In the second C site, C(2) is bonded to one Si(2) and three equivalent Si(1) atoms to form a corner-sharing CSi4 tetrahedral.

The  $2 \times 2 \times 2$  supercell model of 4H-SiC with 64 atoms was shown in Fig. 1(b). The large supercells used in the calculations allow us to simulate the distribution of various dopants and their possible magnetic configurations. We also fixed the c-axis size of the supercell to 20.26 Å (twice the primitive cell in that direction) and varied the lateral size of the cell in the basal directions. The dopants (Mg and V) are fixed at the x-marked position. The Si atom at the marked position is substituted by the doped Mg and V atoms, with the silicon vacancy is labelled as  $V_{Mg-Si}$  and  $V_{V-Si}$  respectively. The selected position x is chosen where both the dopants are mono-doped.

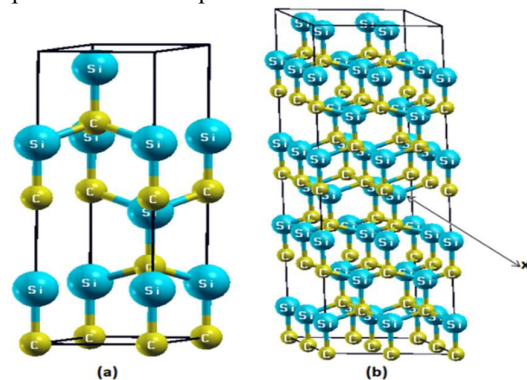


Fig. 1 (a) Optimized Pure 4H SiC (b)  $2 \times 2 \times 2$  supercell model with 64 atoms

*B. Effect of Doping on Crystal Structure*

A single Mg-doped 4H-SiC system was considered first as shown in Fig. 2, with a doping concentration of 1.56%. The hybrid state of Mg and Si after replacing a Si atom with a Mg atom in  $2 \times 2 \times 2$  supercells has been calculated. The results show that the maximum magnetic moment is  $2.23 \mu B$  due to the presence of Mg impurities in the Si site Fig. 2(a). Mg atoms play an important role in the generation of magnetic moments by contributing almost  $1.48 \mu B$  to the total moment.

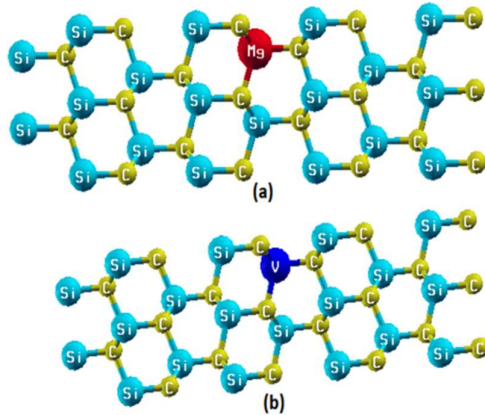


Fig. 2 Substitutional doping model on  $2 \times 2 \times 2$  supercell with 64 atoms at chosen reference point x. (a): Single Mg atom doping and (b) Single V atom doping.

Site x was chosen as the research reference point, as shown in Fig. 1(b). The doping concentration of V-doped 4H-SiC is still 1.56%. As a result, the total magnetic moment of the V-doped 4H-SiC system Fig. 2(b) is about  $3.24 \mu B$  and the V atom plays a major role. Here, a V atom provides a magnetic moment of  $2.62 \mu B$ . Another important effect is the increase in bond length due to the presence of the impurities dopants, the Si-Mg is found to be  $1.89 \text{ \AA}$  and  $2.02 \text{ \AA}$  for Si-V bond length which are greater than that of Si-C  $1.90 \text{ \AA}$  in pure SiC. These results are in good agreement with the theoretical results in [21-23].

*C. Electronic Properties*

*1) Electronic Band Structure 4H-SiC*

Fig. 3 shows our calculated band structure of 4H-SiC crystal with the optimized values, which were also found to be similar to the results reported in [24-25]. From the structure it is clearly shown that the maximum valence band exists at  $\Gamma$  point, while the bottom of the conduction band locates in different k points M, indicating that 4H-SiC is a wide indirect band gap semiconductor with a gap of about  $2.22 \text{ eV}$  which is less than the experimental value of  $3.27 \text{ eV}$  [21-25]. The reason the theoretical value is smaller than the experimental value is that the correlation interaction between excited electrons in the

calculation model has been underestimated [26] but it is still significant for us to analyze the calculated results.

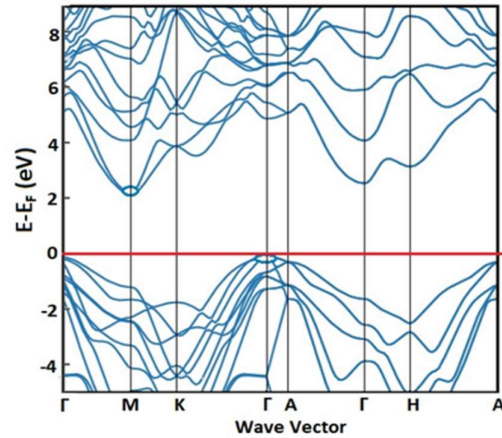


Fig. 3 Calculated Band structure of  $2 \times 2 \times 2$  supercell of 4H SiC with DFT-GGA optimized parameters

*2) Electronic Band Structure single Mg atom doped 4H-SiC*

Fig. 4 shows the calculated band structure of a  $2 \times 2 \times 2$  supercell with 64-atom doping with a single Mg atom (equivalent to 1.56% doping concentration). The structure indicates a half-metallic behavior with the minority spin being semiconducting along a high symmetry point  $\Gamma$ -A- $\Gamma$  and the majority spin being metallic with sufficient unfilled states crossing the Fermi level along symmetric point M. These unfilled states behave like free holes, although slightly localized, also it clearly shows an antiferromagnetic (AFM) ordering. This finding indicates that doping 4H SiC with alkaline earth metals changes it from non-magnetic to AFM order. These results are consistent with many theoretical and experimental results for many wide-bandgap materials [31-32].

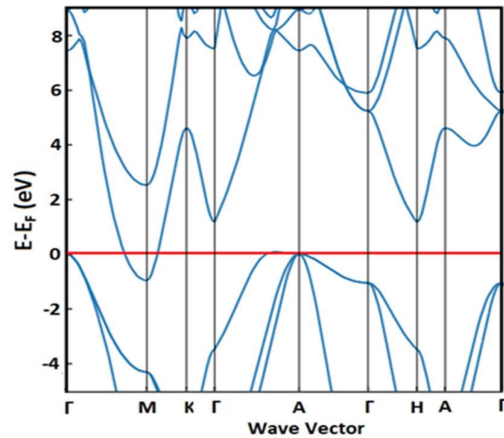


Fig. 4 Calculated Band structure of Mg atom doped  $2 \times 2 \times 2$  supercell of 4H SiC with DFT-GGA optimized parameters

### 3) Electronic Band Structure V doped 4H-SiC

Fig. 5 show the calculated electronic band structure of the Vanadium atom doped 4H SiC. It can be seen that the spin splitting occurs between up spin and down spin channels near the Fermi level, which implies that the V dopants can order magnetism in the  $2 \times 2 \times 2$  supercell of SiC. The doped system shows a metallic nature in which the Fermi energy passes through the conduction and valence band in almost all the high symmetry points. This is completely different when V doped 3H cubic SiC as well as other crystal types [26-28], where the authors found that the system of V doped in 3H cubic SiC is half-metallic. Similarly, from our result, it can be seen that the impurity band merges with the conduction band at higher carrier concentrations and the V dopant acts as a donor in SiC. The V dopant is found to be the main contributor to the ferromagnetic (FM) of the V-doped SiC similar case of the Mg-doped system. To have more clear features of what the band structures say, we calculated the spin-polarized DOS and PDOS of the doped systems. Firstly, we modernized our supercell model by considering two by two of  $2 \times 2 \times 2$  supercell of 4H SiC supercell. The two models of the Mg and V-doped SiC supercell.

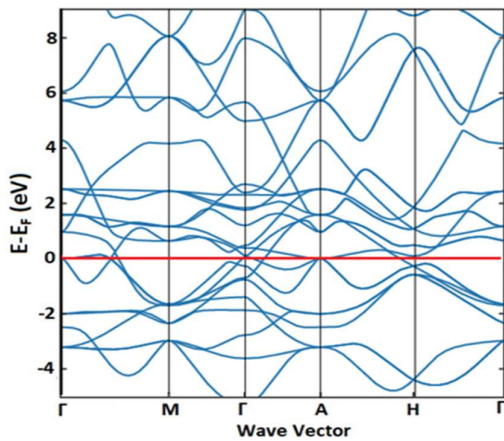


Fig. 5 Calculated Band structure of V atom doped  $2 \times 2 \times 2$  supercell of 4H SiC with DFT-GGA optimized parameters

### 4) DOS and PDOS of Single Mg atom Doped 4H SiC

For our Mg-doped 4H SiC, the calculated DOS and PDOS are presented in Fig. 6 (a) and (b) respectively. From Fig. 6(a), one can see that, due to the Mg impurities, the total DOS indicate that Mg-doped 4H SiC is magnetic in nature with the presence of ferromagnetism (FM) ordered configuration. From Fig. 6(b), the PDOS indicates that the p states of the impurities and host Si atoms overlap significantly in the spin-splitting bands, suggesting a strong hybridization between them.  $2p_{Si}-3p_{V}$  interactions between Mg and neighbouring Si atoms lead to several holes in Mg-doped systems, and therefore the pronounced spin polarization consists mostly of the p orbitals of the nearest neighbour

Si atoms around the dopants. Furthermore, the p orbital of Si atoms is rather spatially extended. In comparison to most of the conventional metal dopants, it is expected that the more spatially extended spin-polarized holes in Si 2p states induced by Mg doping, these results show significant similarities with the case of Mg-doped 3H cubic SiC [30].

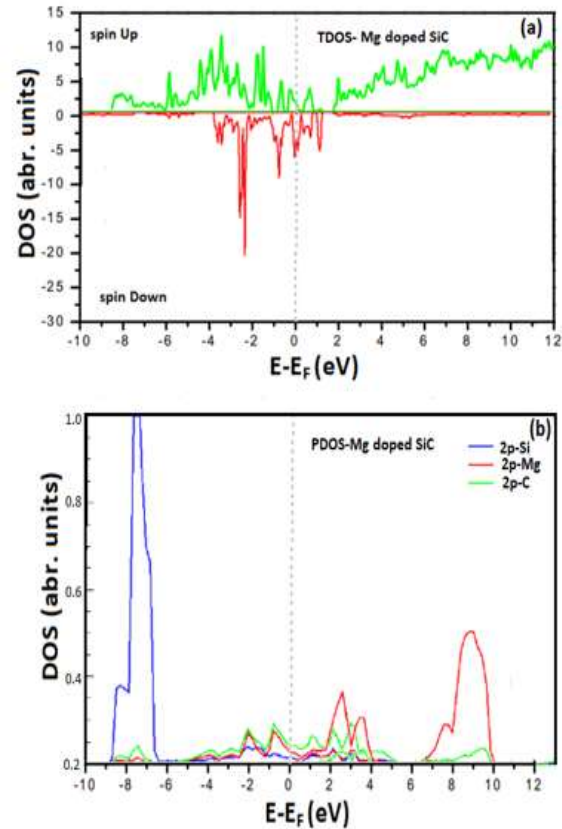


Fig. 6 Calculated (a) Total DOS and (b) PDOS of Mg atom doped 4H SiC

### 5) DOS and PDOS single V atom doped 4H Si

The calculated TDOS and PDOS for V doped 4H SiC are shown in Fig. 7(a) and (b) respectively. The TDOS in Fig. 7(a) indicate that there is evidence of spin-split around the Fermi level, confirming the possible existence of local magnetic moments as predicted by the electronic band structure. The PDOS plot in Fig. 7(b) shows the presence of V marked difference between the spin-majority (occupied) and the spin-minority (unoccupied) states showing prominent energy splitting at the Fermi level, giving rise to spin polarization. Both Fig. 7(a) and (b) indicate that the magnetic moments mainly come from the 2p orbitals of Si atoms and 3d orbitals of the V dopant. The calculated result also shows that the total magnetic moment is  $2.12 \mu_B$  per supercell.

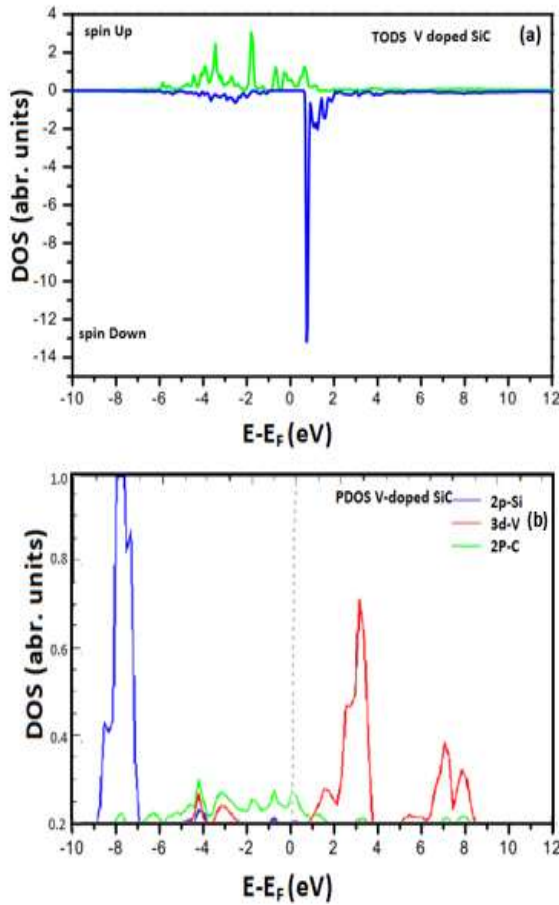


Fig. 7 Calculated (a) Total DOS and (b) PDOS of V atom doped 4H SiC

*D. Magnetic properties*

The effect on the cohesive energy and band gap, with the increase in doping concentration, has been investigated. The concentration is increased by increasing the number of substitutional dopants (Mg and V) in  $2 \times 2 \times 2$  supercell of 4H SiC, i.e. by substituting 2Mg and V, 3Mg and V and 4Mg and V which is equivalent to 3.125%, 4.6875% and 6.25 %A percentages of doping concentration respectively, From the graph of cohesive energy against doping concentration (see Fig. 8 (a)), we observed a significant increase in a regular manner in both dopants cases, that is as increase the doping concentration the cohesive energy also increases which shows that the structure will become more unstable [33]. Nonetheless, in the case of Band-gap against doping concentration Fig. 8(b) as we increase the doping concentration the band gap is decrease in all the dopants situations. At a point when maximum doping concentration (6.25%) becomes consistent, however variety in doping concentration sites a significant change happens in the band gap of all the doped systems.

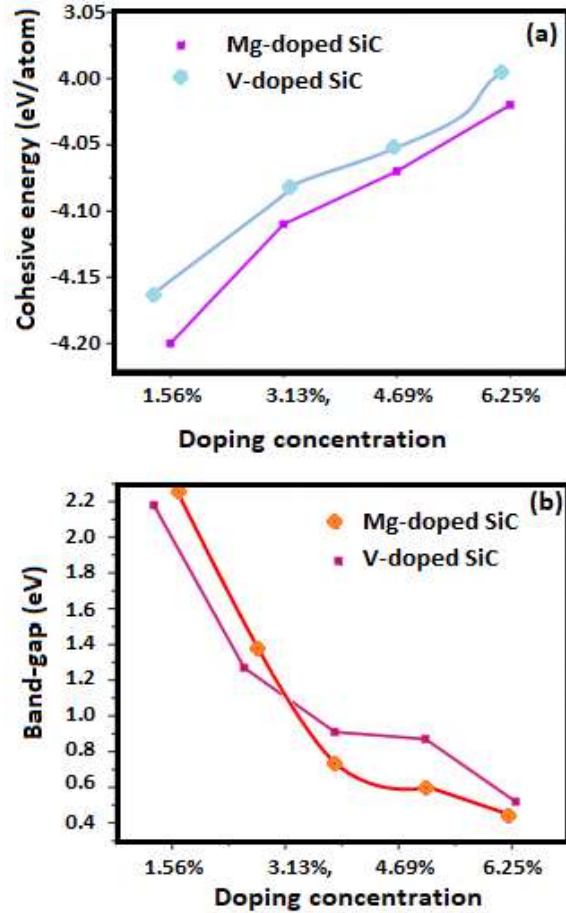


Fig. 8 (a) The graph between doping concentration and cohesive energy (b) The graph between doping concentration and band gap.

IV. CONCLUSION

In conclusion, we have systematically investigated the effect of Mg and V atoms doping 4H-SiC within the framework of DFT-GGA as implemented in Quantum ESPRESSO. The following deductions have been drawn:

1. The presence of both alkaline earth metal and transition metal into a non-magnetic 4H-SiC compound can significantly transform it into a magnetic material with a significant magnetic moment.
2. The electronic band structure of pure 4H-SiC is a wide indirect band gap semiconductor with a gap of about 2.21 eV which is less than the experimental value of 3.27 eV [34], and also observed a half-metallic behavior with the minority spin being semiconducting along a high symmetry point  $\Gamma$ -A- $\Gamma$  and the majority spin being metallic with sufficient unfilled states crossing the Fermi level along symmetric point M.
3. Introducing Mg and V impurities completely shrinks the band gap and turns the material into a metallic

nature, also making a Fermi energy pass through the conduction and valence band in almost all the high symmetry points. The V dopant is found to be the main contributor to the ferromagnetic (FM) of the V-doped SiC similar case of the Mg-doped system. These results show that the doped systems can be a favorable candidate in Spintronic applications.

4. Finally, by varying the doping concentration in increasing paths, the band gap will continue to decrease until a maximum concentration is achieved where the band gap shrinks completely while the cohesive energy is also increased.

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